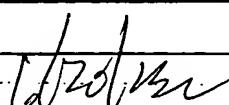


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2434		PRIORITY SERIAL NO. 10422339 10/6 97013	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micro Technology, Inc.			
				PRIORITY FILING DATE 4/11/2002		PRIORITY GROUP 1705 1762	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,951,887	9/14/99	MABUCHI et al.			
	AB	6,446,573	9/10/02	HIRAYAMA et al.			
	AC	5,988,104	11/23/99	NAMBU			
	AD	5,788,778	8/4/98	SHANG et al.			
	AE	6,347,602	2/19/2002	GOTO et al.			
	AF	5,645,644	7/8/1997	MABUCHI et al.			
	AG	6,311,638	11/6/2001	ISHII et al.			
	AH	5,545,258	8/13/96	KATAYAMA et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AI						Yes
	AJ						No
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK						
	AL						
	AM						
	AN						
	AO						
EXAMINER 				DATE CONSIDERED 			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2434		PRIORITY SERIAL NO. 10434920-101697013	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					PRIORITY FILING DATE 4/11/2002		PRIORITY GROUP 1762	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
<i>MM</i>	AA	6,527,908	3/4/2003	KANETSUKI et al.				
	AB	6,158,383	12/12/2000	WATANABE et al.				
	AC	5,134,965	8/4/1992	TOKUDA et al.				
	AD							
	AE							
	AF							
	AG							
	AH							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
								Yes
	AI							No
	AJ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AK							
	AL							
	AM							
	AN							
EXAMINER <i>MM</i>				DATE CONSIDERED <i>6/20/05</i>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

EL979952795

Form PTO-1449  LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2434		SERIAL NO. 10/699,013	
					APPLICANT Craig M. Carpenter et al.		FILING DATE October 30, 2003		GROUP NO. 4334- 1767	
U.S. PATENT DOCUMENTS										
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate		
<i>WY</i>	AA	5,749,966	05/98	Shates		<i>S</i>	<i>S</i>	<i>S</i>		
<i>WY</i>	AB	5,698,036	12/97	Ishii et al.		<i>S</i>	<i>S</i>	<i>S</i>		
<i>WY</i>	AC	6,040,021	03/00	Miyamoto		<i>S</i>	<i>S</i>	<i>S</i>		
<i>WY</i>	AD					<i>S</i>	<i>S</i>	<i>S</i>		
	AE					<i>S</i>	<i>S</i>	<i>S</i>		
	AF					<i>S</i>	<i>S</i>	<i>S</i>		
	AG					<i>S</i>	<i>S</i>	<i>S</i>		
FOREIGN PATENT DOCUMENTS										
		Document Number	Date	Country	Class	Subclass	Translation			
							Yes	No		
<i>WY</i>	AH	EP 1 115 147 A1	07/01	EPO						
<i>WY</i>	AI	0 520 832 A1	12/92	EPO						
	AJ	US-03/09913	03/03	PCT Search Report						
	AK			NOT A PUBLICATION						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)										
	AL									
	AM									
	AN									
	AO									
	AP	<i>WY</i>								
EXAMINER				DATE CONSIDERED						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										